

<b>Notice of References Cited</b>	Application/Control No. 10/533,751		Applicant(s)/Patent Under Reexamination DEPPE ET AL.	
	Examiner Gayla Futel		Art Unit 2609	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,654,813 A	08-1997	Whitworth, Thomas W.	398/111
*	B	US-5,710,911 A	01-1998	Walsh et al.	713/500
*	C	US-6,157,265 A	12-2000	Hanjani, Hassan	331/49
*	D	US-2002/0036910 A1	03-2002	Yang, Jun-Hyun	363/21.07
*	E	US-2002/0163905 A1	11-2002	Brabrand, Tord	370/347
*	F	US-5,638,054	06-1997	Davis et al.	340/7.39
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O	JP 08023581 A	01-1996	Japan	HIGASHIHARA, MORIO	
	P	GB 2324688 A	10-1998	United Kingdom	SLACK, ROGER	
	Q	JP 10032544 A	02-1998	Japan	YOSHIZAWA, JUNICHI	
	R	JP 09231193 A	09-1997	Japan	YAMADA, FUMIE	
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.